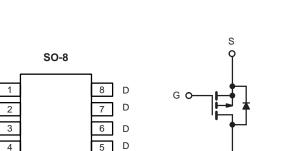
S

Top View



P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^d	Q _g (Typ.)			
- 30	0.0125 at V _{GS} = - 10 V	- 11.6	22 nC			
	0.0180 at $V_{GS} = -4.5 \text{ V}$	- 10	22 110			



P-Channel MOSFET

FEATURES

- Halogen-free According to IEC 61249-2-21 **Available**
- TrenchFET® Power MOSFET
- 100 % R_g Tested
 100 % UIS Tested

COMPLIANT HALOGEN **FREE**

APPLICATIONS

- · Load Switches
 - Notebook PCs
 - Desktop PCs

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	- 30	V		
Gate-Source Voltage	V _{GS}	± 20			
	T _C = 25 °C		- 11.6		
Continuous Drain Current (T _{.I} = 150 °C)	T _C = 70 °C		- 10.5		
Continuous Diairi Curient (1) = 150 °C)	T _A = 25 °C	I _D	- 8.7 ^{a, b}		
	T _A = 70 °C		- 7.7 ^{a, b}	Α	
Pulsed Drain Current	I _{DM}	- 40	A		
Continuous Source-Drain Diode Current	T _C = 25 °C	,	- 4.6		
Continuous Source-Drain Diode Current	T _A = 25 °C	l _s	2.0 ^{a, b}		
Avalanche Current	1 04	I _{AS}	- 20		
Single-Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	20	mJ	
	T _C = 25 °C		5.6		
Maniana Dama Dissination	T _C = 70 °C		3.6	14/	
Maximum Power Dissipation	T _A = 25 °C	P _D	2.5 ^{a, b}	W	
	T _A = 70 °C		1.6 ^{a, b}		
Operating Junction and Storage Temperature Rang	T _J , T _{stq}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{a, c}	t ≤ 10 s	R _{thJA}	39	50	°C/W	
Maximum Junction-to-Foot	Steady State	R _{thJF}	18	22	- C/VV	

- a. Surface mounted on 1" x 1" FR4 board.
- c. Maximum under Steady State conditions is 85 °C/W. d. Based on $T_{\rm C}$ = 25 °C.



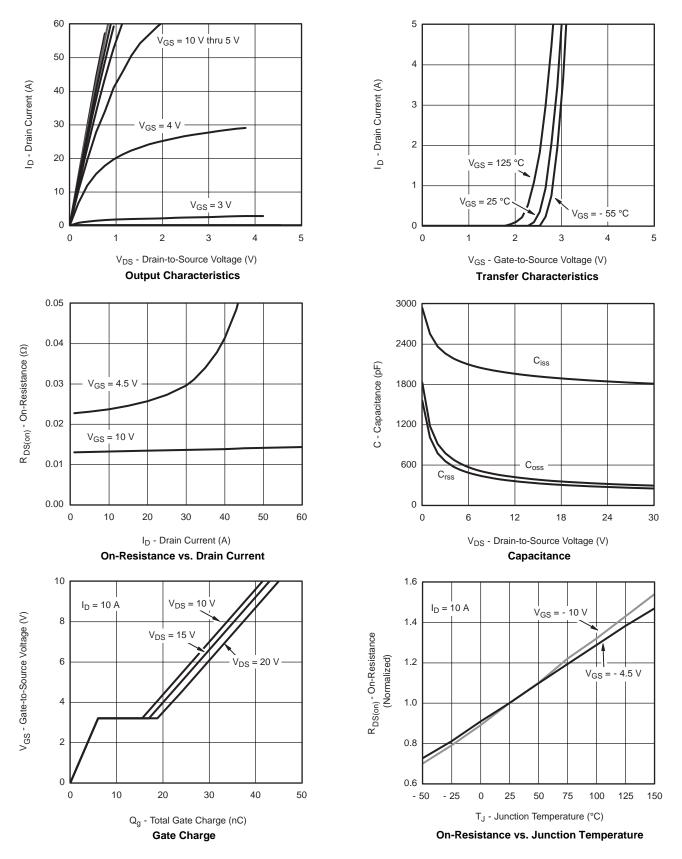
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L = 250 uA		- 31		m\//°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = -250 \mu\text{A}$		5.5		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1.0		- 3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			± 100	nA	
Zama Oata Waltana Basis Osama at	I _{DSS}	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$			- 1		
Zero Gate Voltage Drain Current		V _{DS} = - 30 V, V _{GS} = 0 V, T _J = 55 °C			- 5	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$	- 30			Α	
Davis Ossans Os Otata Basista and	D	V _{GS} = - 10 V, I _D = - 10 A		0.011	0.0125	25	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 7 A		0.012	0.018	Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 10 V, I _D = - 10 A		23		S	
Dynamic ^b							
Input Capacitance	C _{iss}			1960		pF	
Output Capacitance	C _{oss}	V _{DS} = - 15 V, V _{GS} = 0 V, f = 1 MHz		380			
Reverse Transfer Capacitance	C _{rss}			325			
Total Cata Chausa		$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -10 \text{ A}$	43	65			
Total Gate Charge				22	33	nC	
Gate-Source Charge	Q_{gs}	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -10 \text{ A}$		6			
Gate-Drain Charge	Q_{gd}			11			
Gate Resistance	R _g	f = 1 MHz	0.3	1.3	2.5	Ω	
Turn-On Delay Time	t _{d(on)}			11	22		
Rise Time	t _r	$V_{DD} = -15 \text{ V}, R_{L} = 3 \Omega$		13	25		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -5 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		32	50		
Fall Time	ì,			9	18		
Turn-On Delay Time	t _{d(on)}			44	70	ns	
Rise Time	ì,	V_{DD} = - 15 V, R_L = 3 Ω		100	160		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -5 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$		28	50		
Fall Time	t _f			15	30		
Drain-Source Body Diode Characterist	ics						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 4.6	^	
Pulse Diode Forward Current	I _{SM}	-			- 50	Α	
Body Diode Voltage	V _{SD}	I _S = -2 A, V _{GS} = 0 V		- 0.75	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}	7 63		28	45	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	1 2 A d1/d+ 400 A/::- T 05 00		20	40	nC	
Reverse Recovery Fall Time	t _a	$I_F = -2 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		13		200	
Reverse Recovery Rise Time	t _b			15		ns	

Notes:

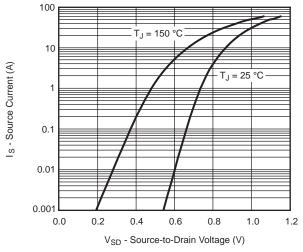
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

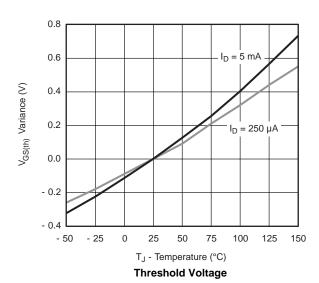


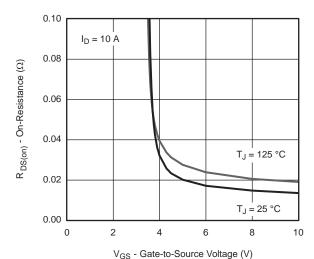




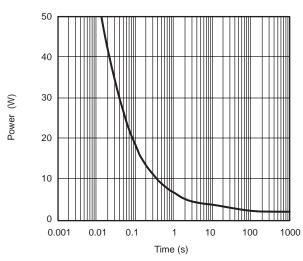


Source-Drain Diode Forward Voltage

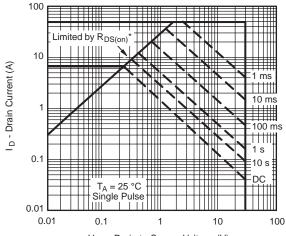




On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power, Junction-to-Ambient

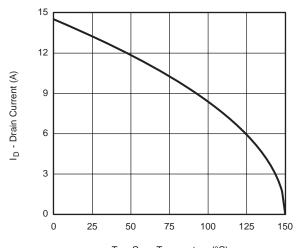


V_{DS} - Drain-to-Source Voltage (V)

Safe Operating Area

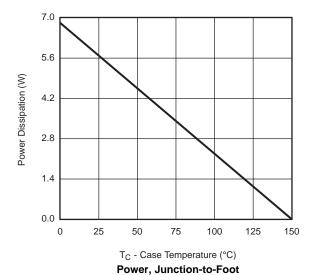
^{*} V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

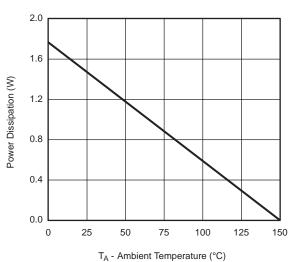




 $T_{\mbox{\scriptsize C}}$ - Case Temperature (°C)

Current Derating*

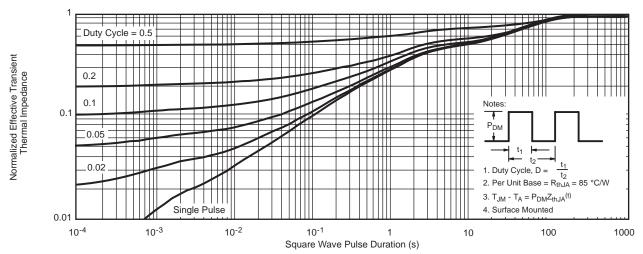




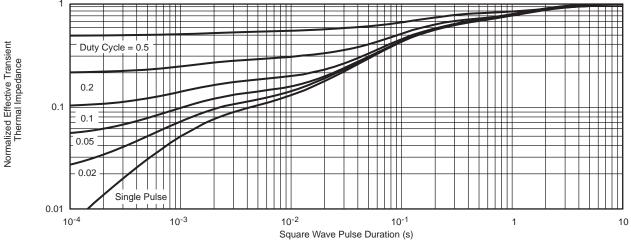
Power Derating, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







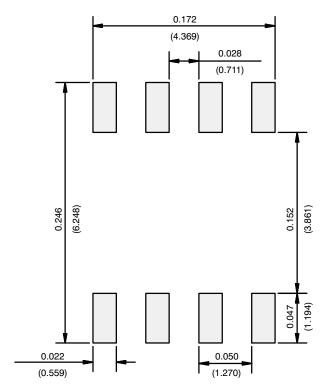
	MILLIM	IETERS	INCHES			
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050 BSC			
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
FCN: C-06527-Rev I 11-Sen-06						

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)

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